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				U.S. PATENT DOCUMENTS				
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	AA	US-5,561,441	10/1996	Hamano				
	AB	US-6,172,662	1/2001	Ito et al.	,			
	AC	US-6,496,170	12/2002	Yoshida et al.				
	AD	US-6,577,289	06/2003	Asao et al.		<del>-</del> 1		
1.1.	AE	US-5,920,301	7/6/1999	K. Sakamoto, et al.	~			
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T.Z	AW	Yasufumi ASAO, et a Chiral Smectic C Pha	I., "Novel Ferro se Transition N	electric Liquid Crystal Mode for Active Ma laterial", Jpn. J. Appl. Phys. Vol. 38, Part	atrix Liquid 1, No. 10,	Crystal Dis	splay Us 999, pgs	ing Cholesteric-
J.Z	AX	Jürg FüNFSCHILLING, et al., "Physics and Electronic Model of Deformed Helix Ferroelectric Liquid Crystal Displays", Jp. J. Appl. Phys. Vol. 33, Part 1, No. 9A, September 1994, pgs. 4950-4959						
1.1	AY	A.G.H. VERHULST, e Active Matrix", Confe	et al., "A Wide V	/iewing Angle Video Display Based on Do f the International Display Research Con	eformed H	elix Ferroel DRC '94), p	ectric LC gs. 377-	C and a Diode 380
	AZ				☐ Add	Additional References sheet(s) attached		
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